

<b>Notice of References Cited</b>	Application/Control No. 10/712,876		Applicant(s)/Patent Under Reexamination PARK ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0101938 A1	06-2003	Ronsse et al.	118/726
*	B	US-6,348,373 B1	02-2002	Ma et al.	438/240
*	C	US-6,780,476 B2	08-2004	Horikawa, Tsuyoshi	427/585
*	D	US-6,784,507 B2	08-2004	Wallace et al.	257/410
*	E	US-6,982,230 B2	01-2006	Cabral et al.	438/778
*	F	US-6,852,194 B2	02-2005	Matsushita et al.	156/345.32
*	G	US-2003/0232501 A1	12-2003	Kher et al.	438/689
*	H	US-2005/0064207 A1	03-2005	Senzaki et al.	428/446
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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